

# EPC2111 – Enhancement-Mode GaN Power Transistor Half-Bridge

$V_{DS}$ , 30 V

$R_{DS(on)}$ , 19 mΩ (Q1), 8 mΩ (Q2)

$I_D$ , 16 A (Q1), 16 A (Q2)



RoHS (Pb) Halogen-Free

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings				
DEVICE	PARAMETER		VALUE	UNIT
Q1	$V_{DS}$	Drain-to-Source Voltage (Continuous)	30	V
		Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	36	
	$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 15^\circ\text{C}/\text{W}$ )	16	A
		Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	50	
	$V_{GS}$	Gate-to-Source Voltage	6	V
		Gate-to-Source Voltage	-4	
	$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
Q2	$V_{DS}$	Drain-to-Source Voltage (Continuous)	30	V
		Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	36	
	$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 36^\circ\text{C}/\text{W}$ )	16	A
		Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	140	
	$V_{GS}$	Gate-to-Source Voltage	6	V
		Gate-to-Source Voltage	-4	
	$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
	$T_{STG}$	Storage Temperature	-40 to 150	



EPC2111 eGaN® ICs are supplied only in passivated die form with solder bumps  
Die Size: 3.5 mm x 1.5 mm

## Applications

- High Frequency DC-DC
- Point-of-Load (POL) Converters

## Benefits

- High Frequency Operation (up to 10 MHz)
- Low Inductance Package
- High Density Footprint

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.3	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	6.6	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	58	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.  
See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details

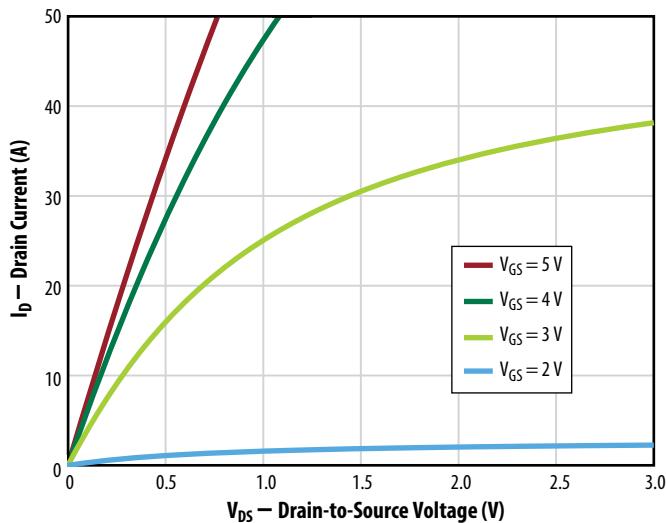
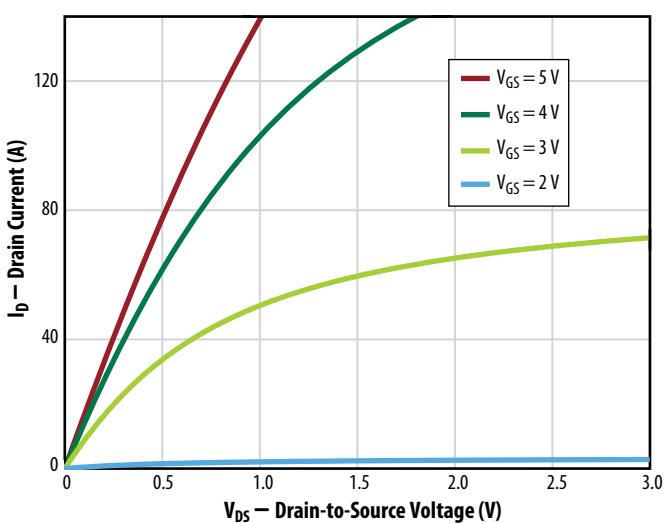
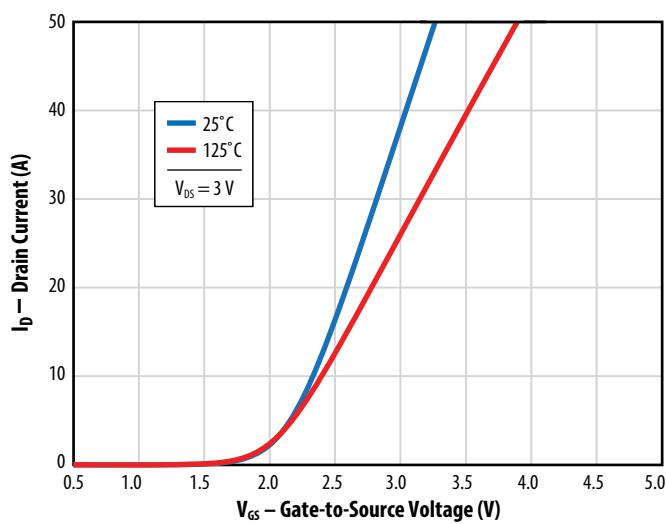
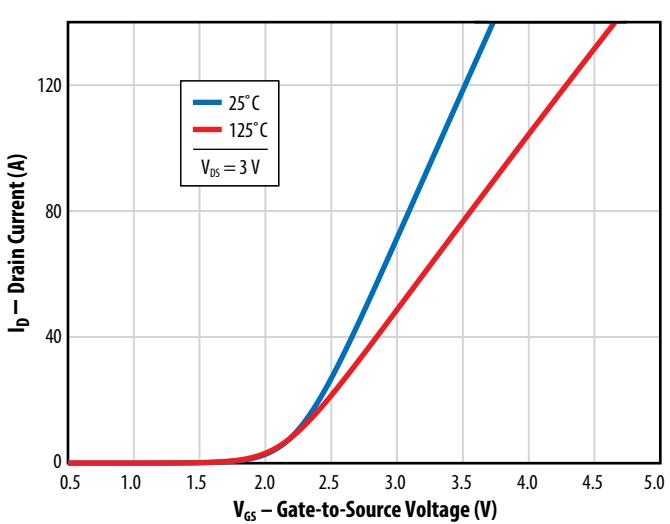
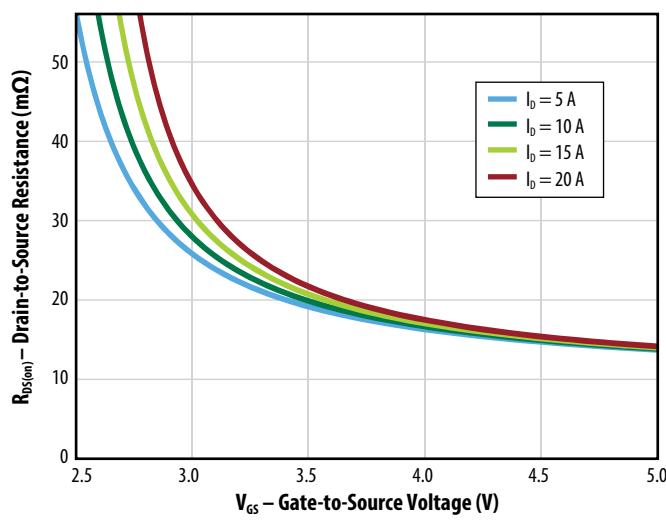
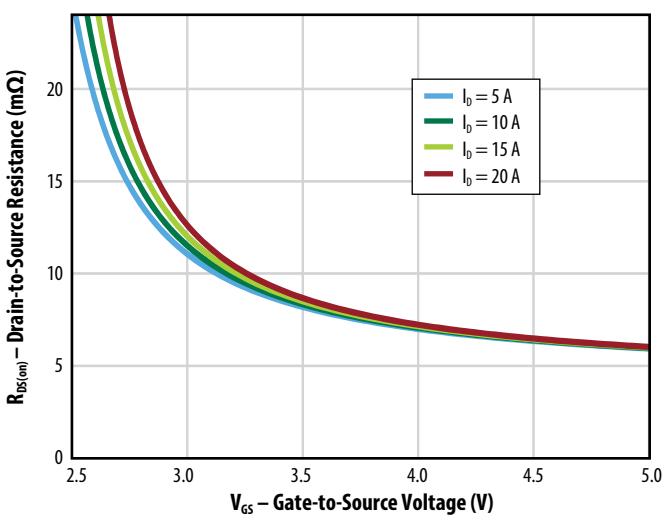
## Static Characteristics

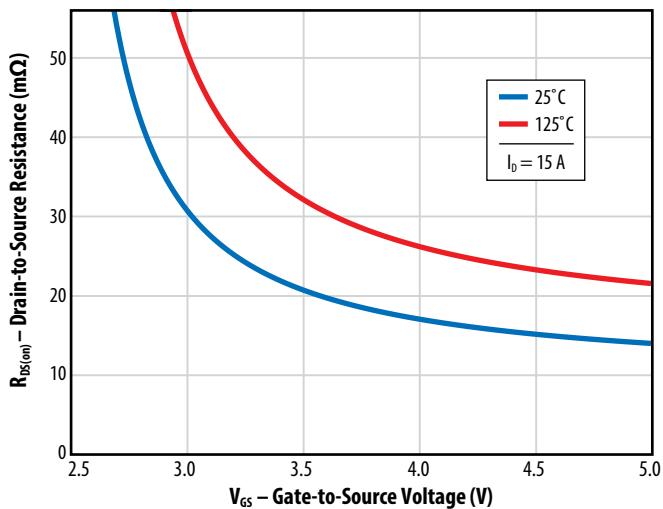
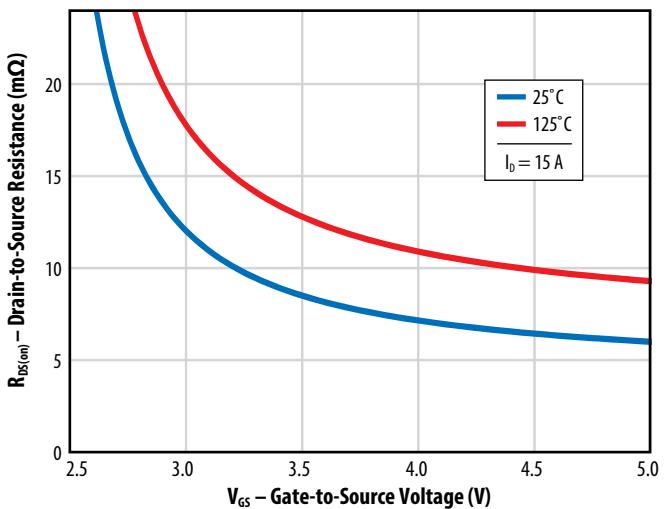
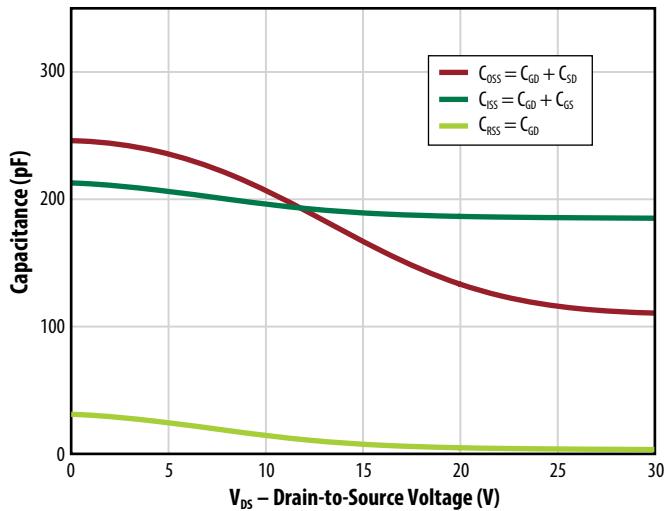
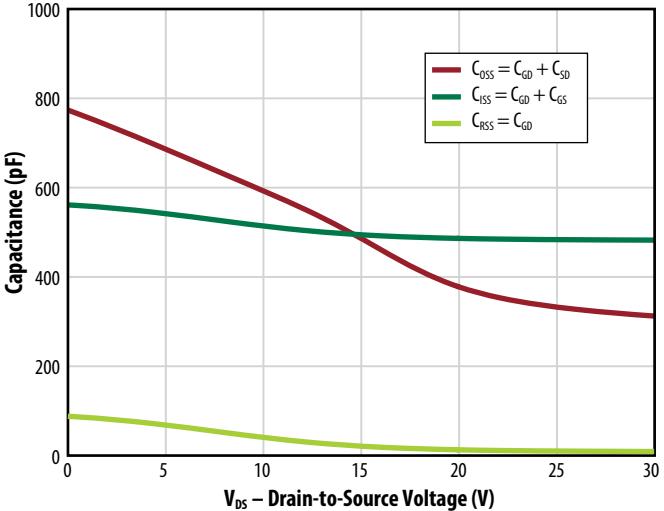
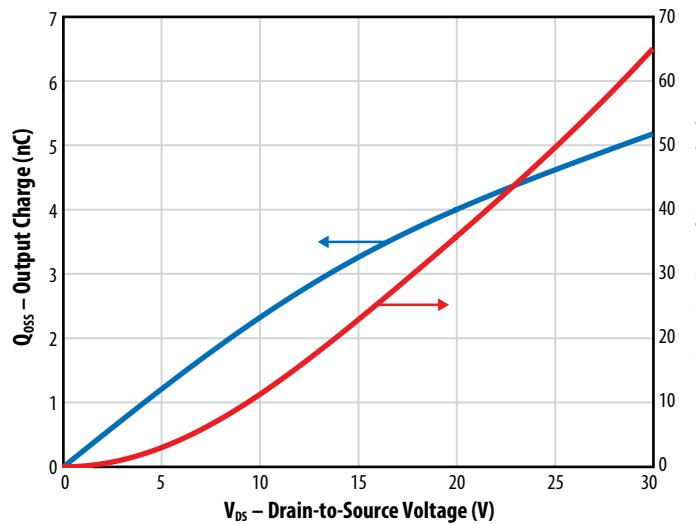
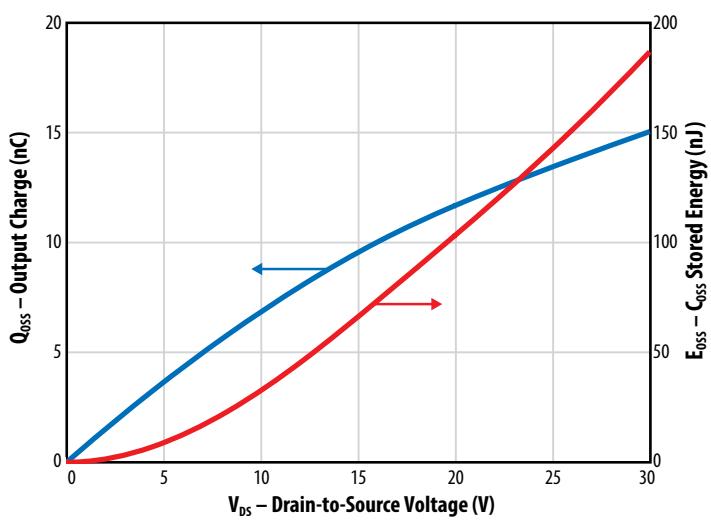
DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1	BV <sub>DSS</sub>	Drain-to-Source Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 0.25 mA	30			V
	I <sub>DSS</sub>	Drain-Source Leakage	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V		0.002	0.15	mA
	I <sub>GSS</sub>	Gate-to-Source Forward Leakage	V <sub>GS</sub> = 5 V		0.004	2	mA
		Gate-to-Source Reverse Leakage	V <sub>GS</sub> = -4 V		0.002	0.15	mA
	V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 2 mA	0.8	1.4	2.5	V
	R <sub>D(on)</sub>	Drain-Source On Resistance	V <sub>GS</sub> = 5 V, I <sub>D</sub> = 15 A		14	19	mΩ
Q2	V <sub>SD</sub>	Source-Drain Forward Voltage	I <sub>S</sub> = 0.5 A, V <sub>GS</sub> = 0 V		1.8		V
	BV <sub>DSS</sub>	Drain-to-Source Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 0.4 mA	30			V
	I <sub>DSS</sub>	Drain-Source Leakage	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V		0.005	0.3	mA
	I <sub>GSS</sub>	Gate-to-Source Forward Leakage	V <sub>GS</sub> = 5 V		0.01	4.5	mA
		Gate-to-Source Reverse Leakage	V <sub>GS</sub> = -4 V		0.005	0.3	mA
	V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 5 mA	0.8	1.4	2.5	V
Q2	R <sub>D(on)</sub>	Drain-Source On Resistance	V <sub>GS</sub> = 5 V, I <sub>D</sub> = 15 A		6	8	mΩ
	V <sub>SD</sub>	Source-Drain Forward Voltage	I <sub>S</sub> = 0.5 A, V <sub>GS</sub> = 0 V		1.8		V

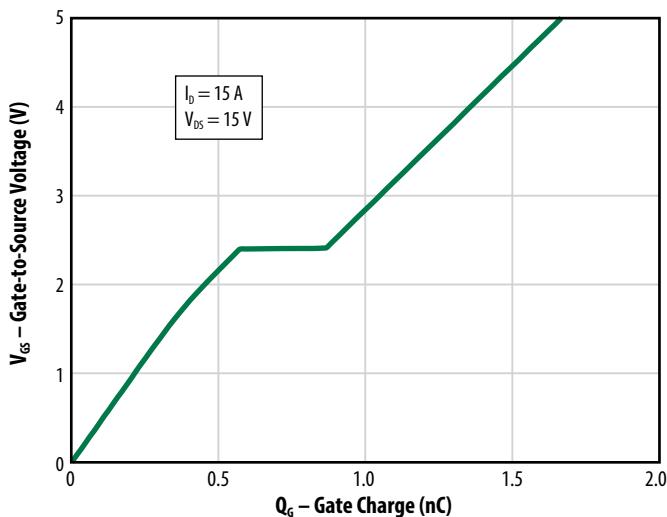
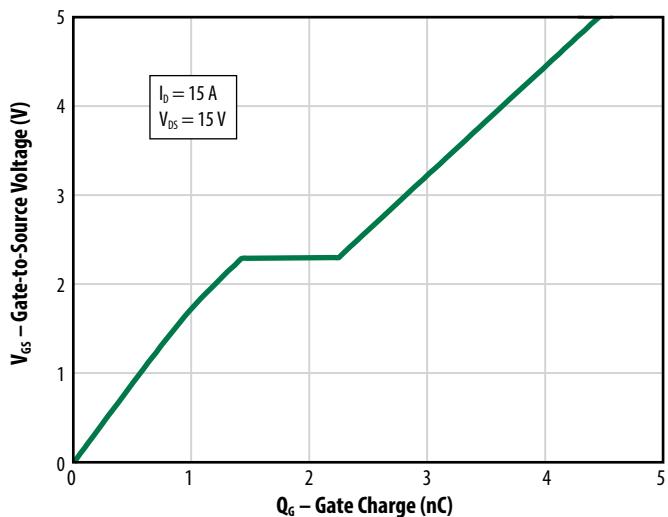
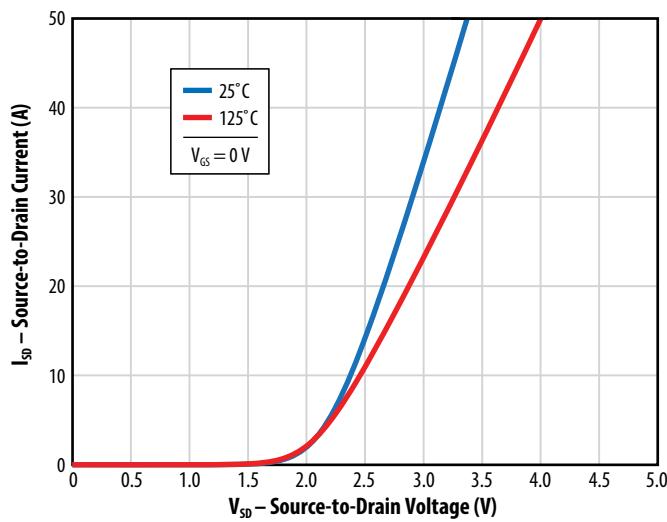
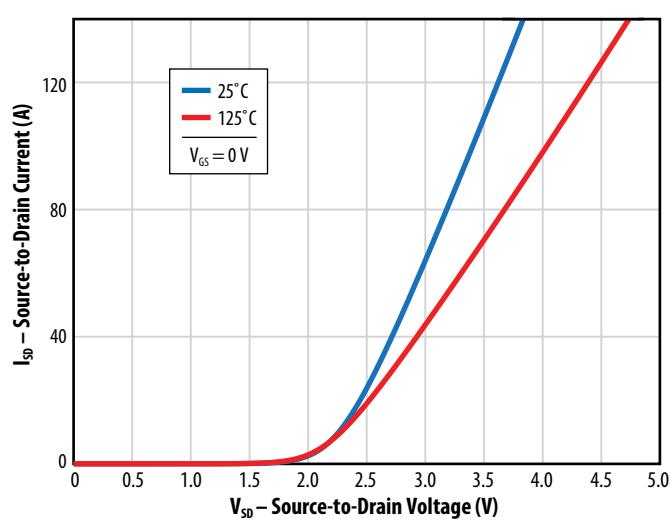
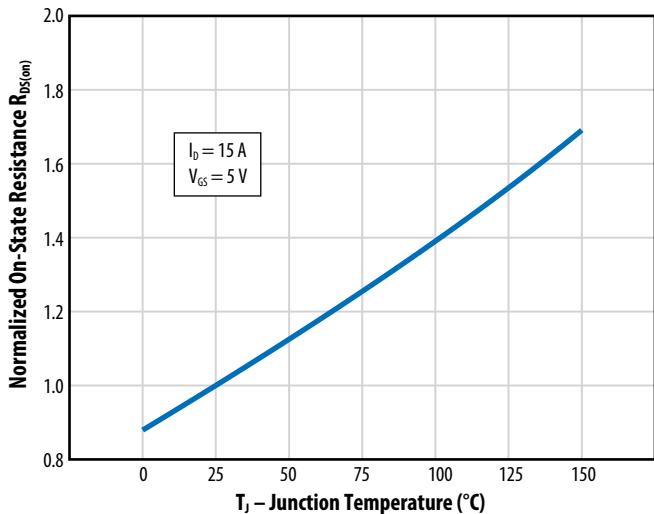
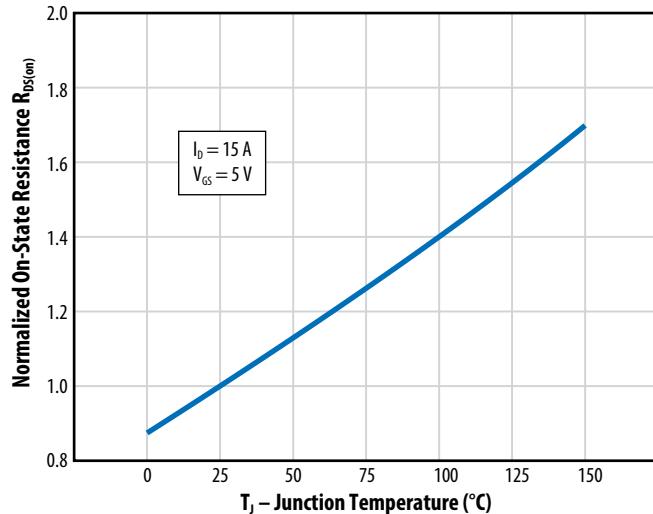
## Dynamic Characteristics

DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1	C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V		190	230	pF
	C <sub>rss</sub>	Reverse Transfer Capacitance			8		
	C <sub>oss</sub>	Output Capacitance			170	255	
	C <sub>oss(er)</sub>	Effective Output Capacitance, Energy Related (Note 2)			204		
	C <sub>oss(tr)</sub>	Effective Output Capacitance, Time Related (Note 3)	V <sub>DS</sub> = 0 to 15 V, V <sub>GS</sub> = 0 V		217		nC
	R <sub>G</sub>	Gate Resistance			0.5		
	Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 15 A	1.7	2.2		nC
	Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A		0.6		
	Q <sub>GD</sub>	Gate-to-Drain Charge			0.3		
	Q <sub>G(TH)</sub>	Gate Charge at Threshold			0.4		
Q2	Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V	3.3	5		pF
	Q <sub>RR</sub>	Source-Drain Recovery Charge			0		
	C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V		495	595	pF
	C <sub>rss</sub>	Reverse Transfer Capacitance			21		
	C <sub>oss</sub>	Output Capacitance			490	735	
	C <sub>oss(er)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>DS</sub> = 0 to 15 V, V <sub>GS</sub> = 0 V		590		nC
	C <sub>oss(tr)</sub>	Effective Output Capacitance, Time Related (Note 3)			637		
	R <sub>G</sub>	Gate Resistance			0.4		
	Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 15 A	4.5	5.8		nC
	Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A		1.4		
	Q <sub>GD</sub>	Gate-to-Drain Charge			0.8		
	Q <sub>G(TH)</sub>	Gate Charge at Threshold			1		
	Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V	9.6	15		
	Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

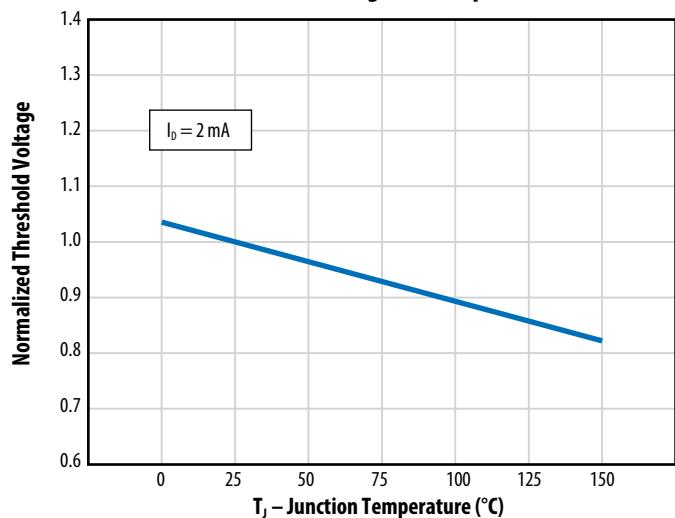
Note 2: C<sub>oss(er)</sub> is a fixed capacitance that gives the same stored energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.Note 3: C<sub>oss(tr)</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

**Figure 1a (Q1): Typical Output Characteristics at 25°C****Figure 1b (Q2): Typical Output Characteristics at 25°C****Figure 2a (Q1): Transfer Characteristics****Figure 2b (Q2): Transfer Characteristics****Figure 3a (Q1):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents****Figure 3b (Q2):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents**

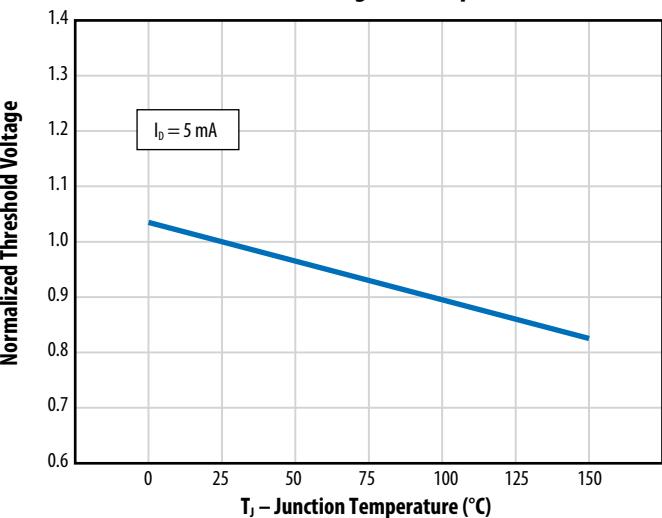
**Figure 4a (Q1):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures****Figure 4b (Q2):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures****Figure 5a (Q1): Capacitance (Linear Scale)****Figure 5b (Q2): Capacitance (Linear Scale)****Figure 6a (Q1): Output Charge and  $C_{OSS}$  Stored Energy****Figure 6b (Q2): Output Charge and  $C_{OSS}$  Stored Energy**

**Figure 7a (Q1): Gate Charge****Figure 7b (Q2): Gate Charge****Figure 8a (Q1): Reverse Drain-Source Characteristics****Figure 8b (Q2): Reverse Drain-Source Characteristics****Figure 9a (Q1): Normalized On-State Resistance vs. Temperature****Figure 9b (Q2): Normalized On-State Resistance vs. Temperature**

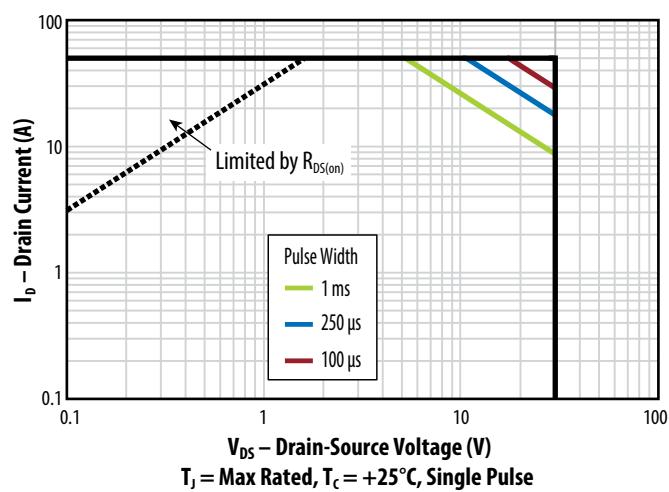
**Figure 10a (Q1):**  
Normalized Threshold Voltage vs. Temperature



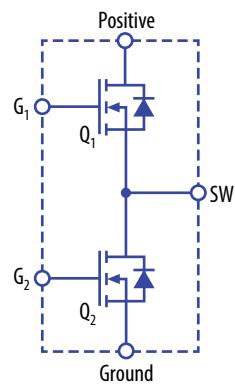
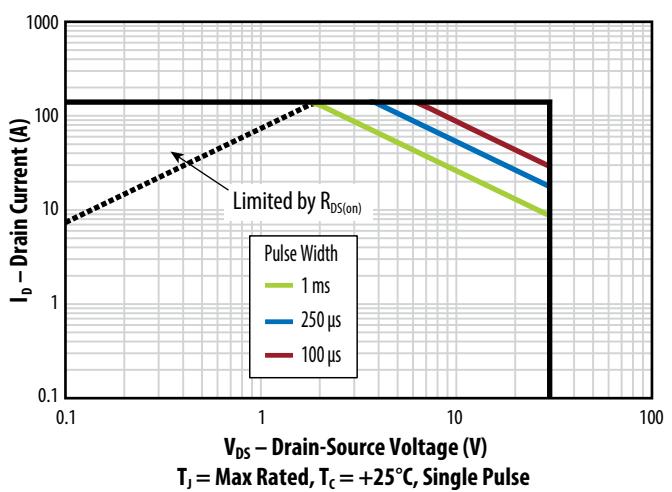
**Figure 10b (Q2):**  
Normalized Threshold Voltage vs. Temperature



**Figure 11a (Q1): Safe Operating Area**

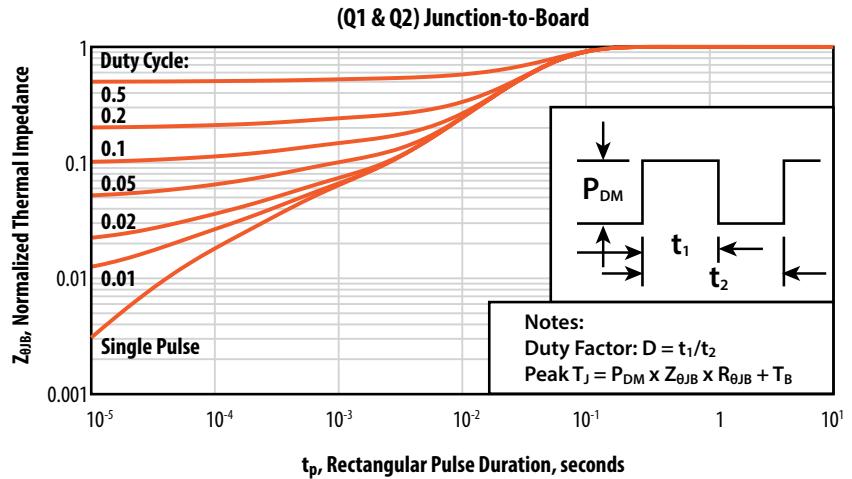


**Figure 11b (Q2): Safe Operating Area**

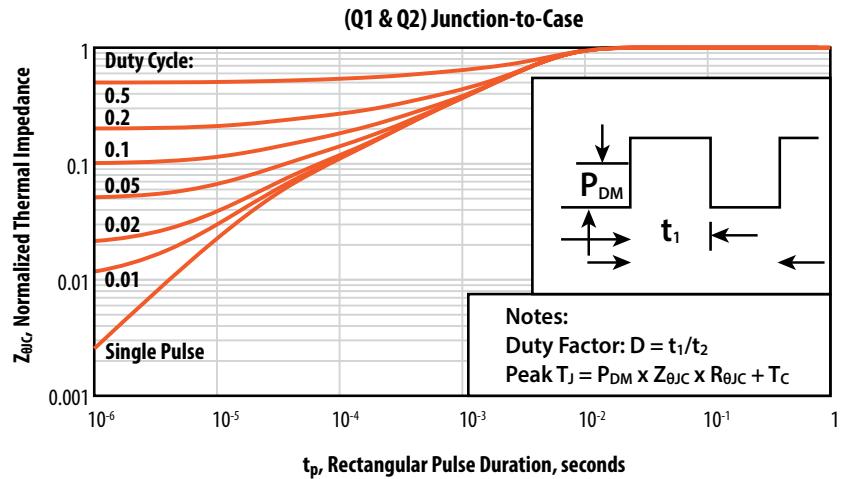


**Figure 12**  
Typical Application Circuit

**Figure 13a**  
Transient Thermal Response Curves

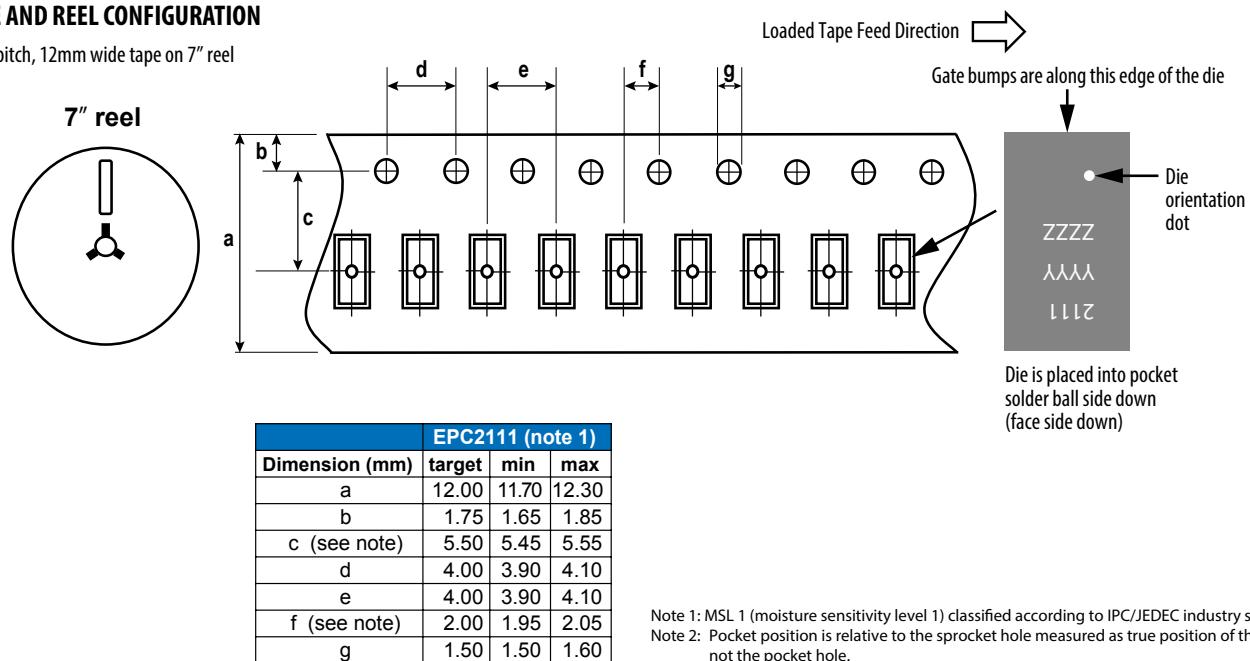
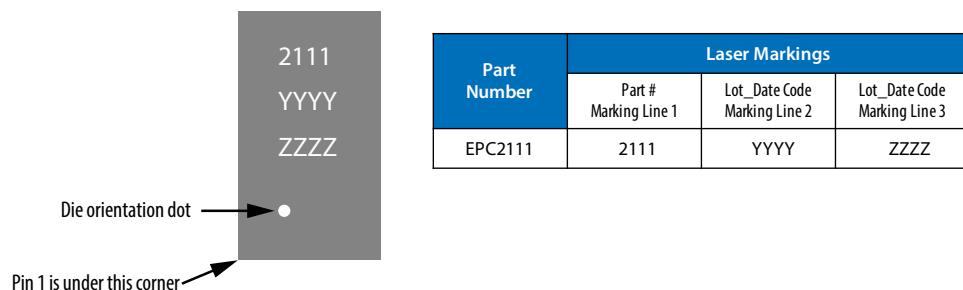


**Figure 13b**  
Transient Thermal Response Curves



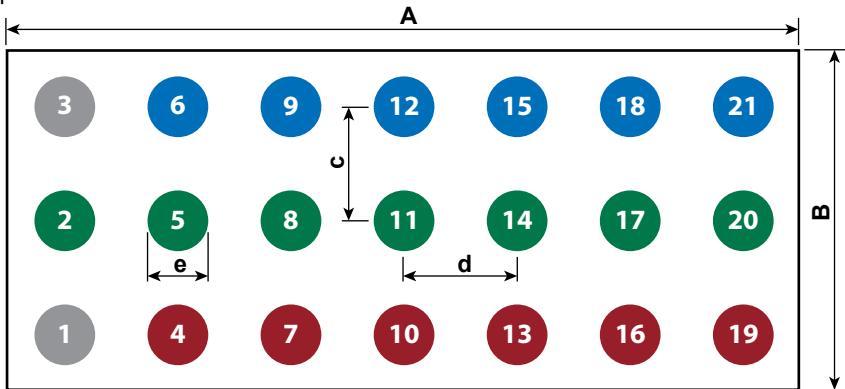
**TAPE AND REEL CONFIGURATION**

4mm pitch, 12mm wide tape on 7" reel

**DIE MARKINGS**

**DIE OUTLINE**

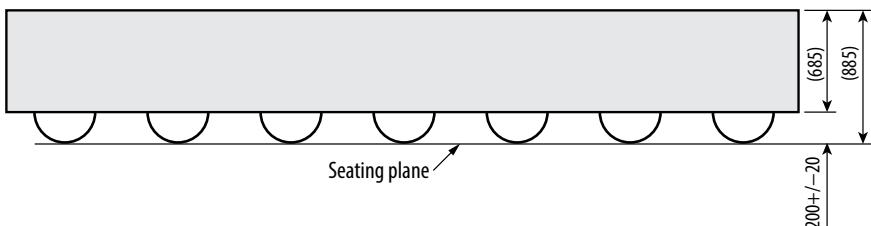
Solder Bump View



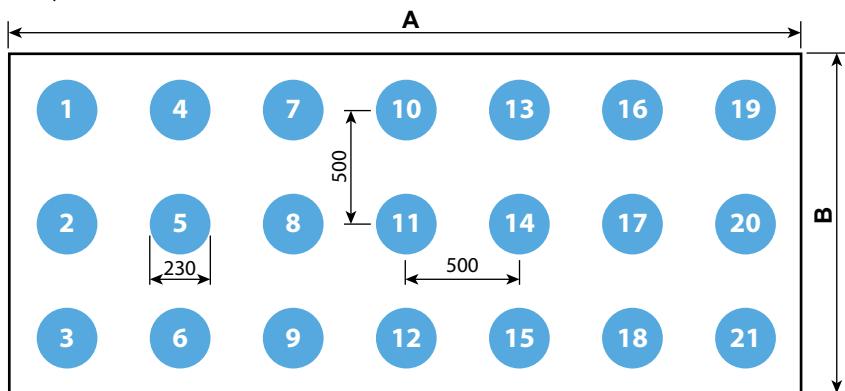
DIM	MIN	Nominal	MAX
A	3470	3500	3530
B	1470	1500	1530
c	500	500	500
d	500	500	500
e	238	264	290

Pad 1 is G1; Pad 3 is G2;  
**Pads 4, 7, 10, 13, 16, 19 are V<sub>IN</sub>;**  
**Pads 2, 5, 8, 11, 14, 17, 20 are SN;**  
**Pads 6, 9, 12, 15, 18, 21 are GND**

Side View

**RECOMMENDED LAND PATTERN**

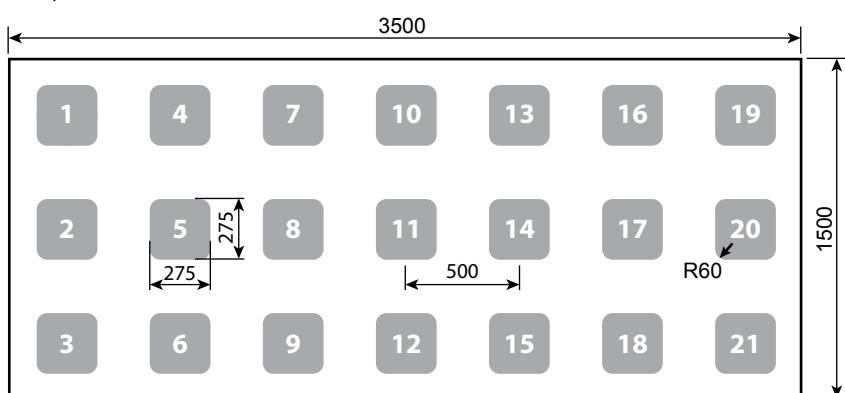
(measurements in µm)



The land pattern is solder mask defined.  
Solder mask is 10 µm smaller per side than bump.

**RECOMMENDED STENCIL DRAWING**

(measurements in µm)



Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, openings per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at:  
<https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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Information subject to change without notice.

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